

# $\begin{array}{c} {}^{\text{May2012}}\\ \textbf{Ultra} \ \textbf{FRFET}^{^{\text{TM}}} \end{array}$

# FDP5N50U / FDPF5N50UT N-Channel MOSFET, FRFET 500V, 4A, 2.0 $\Omega$

#### **Features**

- $R_{DS(on)}$  = 1.65 $\Omega$  ( Typ.)@  $V_{GS}$  = 10V,  $I_D$  = 2A
- Low gate charge (Typ. 11nC)
- Low C<sub>rss</sub> (Typ. 5pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · RoHS compliant



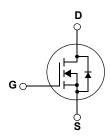
# **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DOMS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutationmode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.







# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter				Units	
$V_{DSS}$	Drain to Source Voltage	Drain to Source Voltage			500		
$V_{GSS}$	Gate to Source Voltage			±	30	V	
	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		4	4*	۸	
ID	Drain Current	-Continuous (T <sub>C</sub> = 100°C)		2.4	2.4*	Α	
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	16	16*	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 2)	216		mJ	
I <sub>AR</sub>	Avalanche Current		(Note 1)	4		Α	
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	8.5		mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20		V/ns	
D	Dower Dissipation	(T <sub>C</sub> = 25°C)		85	28	W	
$P_{D}$	Power Dissipation	- Derate above 25°C		0.67	0.22	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to	+150	οС	
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			3	00	°C	

<sup>\*</sup>Drain current limited by maximum junction temperature

### **Thermal Characteristics**

Symbol	Parameter I		FDPF5N50UT	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case		4.5	
$R_{\thetaCS}$	Thermal Resistance, Case to Sink Typ.		-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

# Package Marking and Ordering Information T<sub>C</sub> = 25°C unless otherwise noted

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FDP5N50U	FDP5N50U	TO-220	-	-	50
FDPF5N50UT	FDPF5N50UT	TO-220F	-	-	50

# **Electrical Characteristics**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$ , $V_{GS} = 0 V$ , $T_J = 25 ^{\circ} C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.7	-	V/°C
1	Zana Cata Valtana Brain Current	V <sub>DS</sub> = 500V, V <sub>GS</sub> = 0V	-	-	25	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 400V, T_C = 125^{\circ}C$	-	-	250	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

#### On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage $V_{GS} = V_{DS}$ , $I_D = 250\mu A$	3	-	5	V
R <sub>DS(on</sub>	Static Drain to Source On Resistance $V_{GS} = 10V$ , $I_D = 2A$	-	1.65	2	Ω
g <sub>FS</sub>	Forward Transconductance $V_{DS} = 40V$ , $I_D = 2A$ (Note 4)	-	4.8	-	S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05V V 0V	-	485	650	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V f = 1MHz		65	90	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/12	-	5	8	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	11	15	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 4A$	-	3	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V (Note 4, 5)	-	5	-	nC

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	14	38	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 250V, I_{D} = 4A$		-	21	52	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25\Omega$		-	27	64	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)	-	20	50	ns

### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	-	4	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	-	16	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 4A		-	-	1.6	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 4A		-	36	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	(Note 4)	-	33	-	nC

- Notes:

  1: Repetitive Rating: Pulse width limited by maximum junction temperature 
  2: L = 27mH,  $I_{AB}$  = 4A,  $V_{DB}$  = 50V,  $R_{G}$  = 25Ω, Starting  $T_{J}$  = 25°C 
  3:  $I_{SD}$  ≤ 4A, di/dt ≤ 200 $A/\mu$ s,  $V_{DB}$  5 $B/\nu_{DSS}$ , Starting  $T_{J}$  = 25°C 
  4: Pulse Test: Pulse width ≤ 300 $\mu$ s, Duty Cycle ≤ 2% 
  5: Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

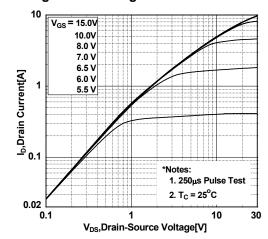


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

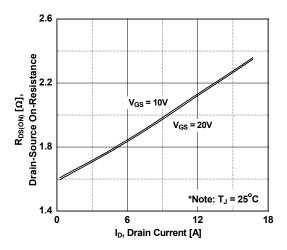


Figure 5. Capacitance Characteristics

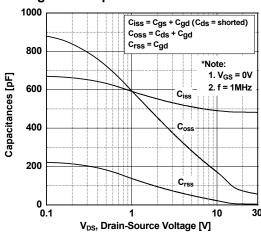


Figure 2. Transfer Characteristics

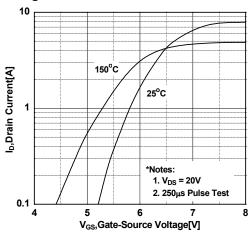


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

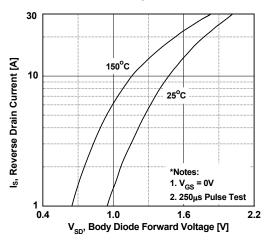
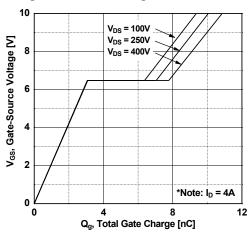


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

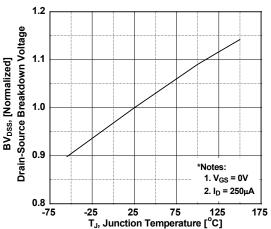


Figure 9. Maximum Safe Operating Area - FDPF5N50UT

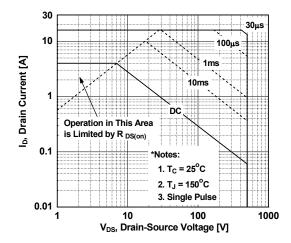


Figure 8. Maximum Safe Operating Area - FDP5N50U

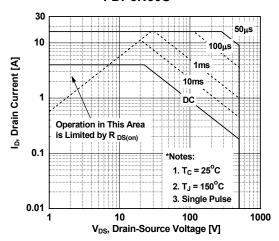


Figure 10. Maximum Drain Current vs. Case Temperature

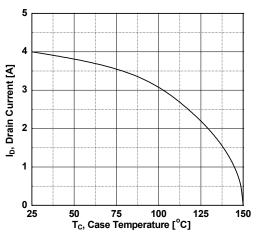
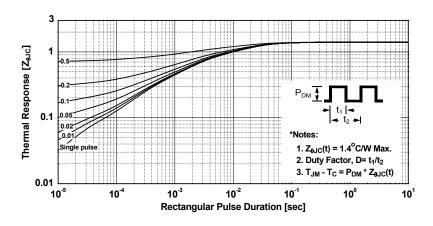
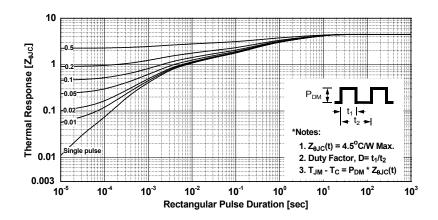


Figure 11. Transient Thermal Response Curve - FDP5N50U

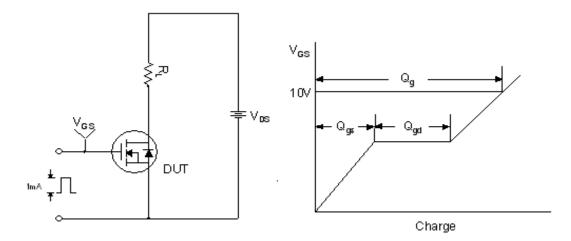


# **Typical Performance Characteristics** (Continued)

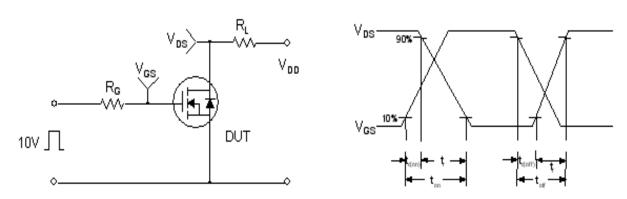




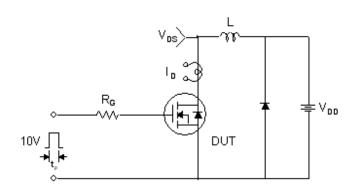
# **Gate Charge Test Circuit & Waveform**

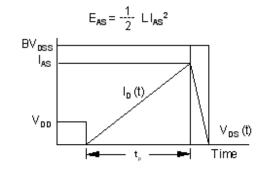


# **Resistive Switching Test Circuit & Waveforms**

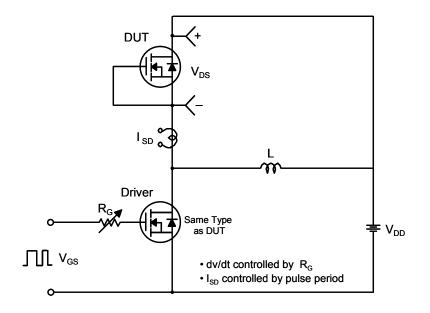


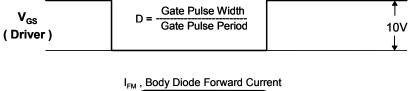
# **Unclamped Inductive Switching Test Circuit & Waveforms**

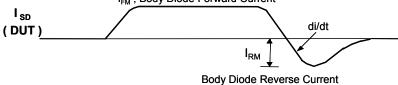


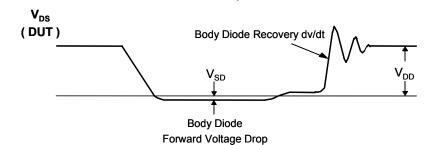


### Peak Diode Recovery dv/dt Test Circuit & Waveforms



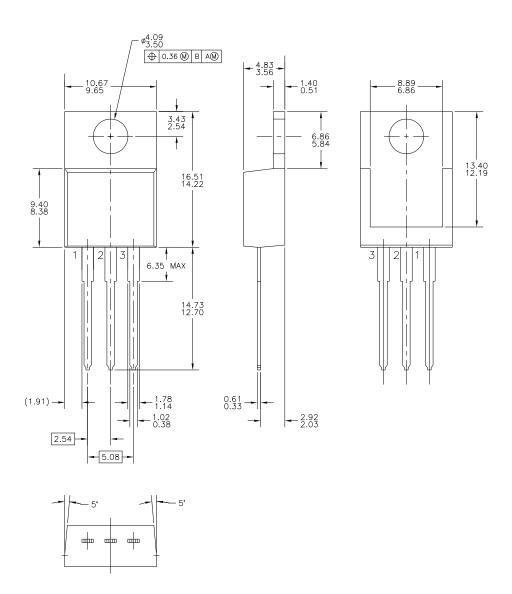






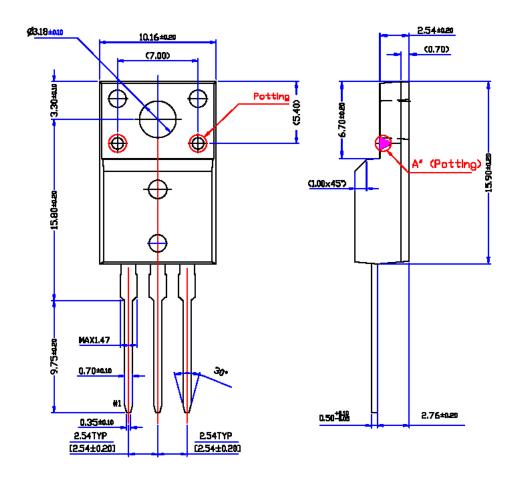
# **Mechanical Dimensions**

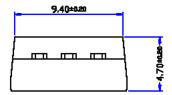
# TO-220



# **Package Dimensions**

# TO-220F Potted





\* Front/Back Side Isolation Voltage : AC 2500V

**Dimensions in Millimeters** 





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